

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO.		APPLICATION NO.	
				TROLOGY 02.02		10/536.576	
				APPLICANT(S) Szwajkowski et al.			
				FILING DATE February 6, 2006		GROUP ART UNIT	

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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
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/HL/	DE 196 52 113	18.06.1998	Germany				
/HL/	WO 2004/051182	17.06.2004	PCT	G01B	9/02		

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/HL/		Nakadate et al., "Real-Time Fringe Patter Processing and its Applications", Proc. of SPIE, Vol. 2544, pps. 74-86, June 1995 (abstract only).	

EXAMINER /Hwa Lee/	DATE CONSIDERED 12/22/2007
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				Szwajkowski et al.			
				FILING February 6, 2006		GROUP ART	

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FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

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/HL/			Sivakumar, et al., "Large Surface Profile Measurement with Instantaneous Phase-Shifting Interferometry", Optical Engineering, February 2003, Vol. 42, Issue 2, pps. 367-372 (abstract only).
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